



ALPHA & OMEGA
SEMICONDUCTOR

AOTS26108
30V/20V Complementary MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- RoHS and Halogen-Free Compliant

Applications

- This device is ideal for Load Switch

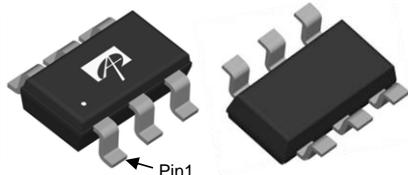
Product Summary

N-Channel	P-Channel
$V_{DS} = 30V$	-20V
$I_D = 3.8A$ ($V_{GS}=10V$)	-4.5A ($V_{GS}=-4.5V$)
$R_{DS(ON)} < 50m\Omega$ ($V_{GS}=10V$)	$R_{DS(ON)} < 44m\Omega$ ($V_{GS}=-4.5V$)
$< 57m\Omega$ ($V_{GS}=4.5V$)	$< 59m\Omega$ ($V_{GS}=-2.5V$)
$< 72m\Omega$ ($V_{GS}=2.5V$)	$< 80m\Omega$ ($V_{GS}=-1.8V$)

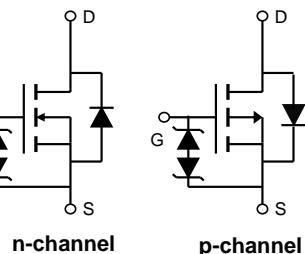
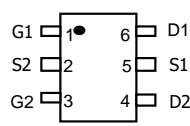
ESD protection



Top View TSOP6 Bottom View



Top View



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Max n-channel	Max p-channel	Units
Drain-Source Voltage	V_{DS}	30	-20	V
Gate-Source Voltage	V_{GS}	± 12	± 8	V
Continuous Drain Current	I_D	3.8	-4.5	A
$T_A=70^\circ C$		3	-3.6	
Pulsed Drain Current ^C	I_{DM}	15	-18	
Power Dissipation ^B	P_D	1.25	1.25	W
$T_A=70^\circ C$		0.80	0.80	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150		°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	75	100	°C/W
Maximum Junction-to-Ambient ^{A,D}		105	130	°C/W
Maximum Junction-to-Lead	$R_{\theta JL}$	50	65	°C/W

N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=30\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	0.5	1	1.5	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=3.8\text{A}$ $T_J=125^\circ\text{C}$		40	50	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}, I_D=3.6\text{A}$		42	57	$\text{m}\Omega$
		$V_{GS}=2.5\text{V}, I_D=3.2\text{A}$		50	72	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=5\text{V}, I_D=3.8\text{A}$		20		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.7	1	V
I_S	Maximum Body-Diode Continuous Current				1.5	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=15\text{V}, f=1\text{MHz}$		340		pF
C_{oss}	Output Capacitance			30		pF
C_{rss}	Reverse Transfer Capacitance			25		pF
R_g	Gate resistance	$f=1\text{MHz}$	4	8	12	Ω
SWITCHING PARAMETERS						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, I_D=3.8\text{A}$		8	16	nC
$Q_g(4.5\text{V})$	Total Gate Charge			4	8	nC
Q_{gs}	Gate Source Charge			1		nC
Q_{gd}	Gate Drain Charge			1.2		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=15\text{V}, R_L=3.95\Omega, R_{\text{GEN}}=3\Omega$		2.5		ns
t_r	Turn-On Rise Time			3		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			30		ns
t_f	Turn-Off Fall Time			5		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=3.8\text{A}, di/dt=500\text{A}/\mu\text{s}$		5.5		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=3.8\text{A}, di/dt=500\text{A}/\mu\text{s}$		4		nC

A. The value of R_{thJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{thJA} is the sum of the thermal impedance from junction to lead R_{thJL} and lead to ambient.

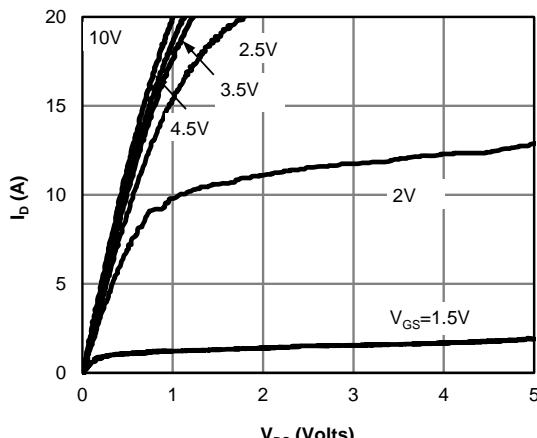
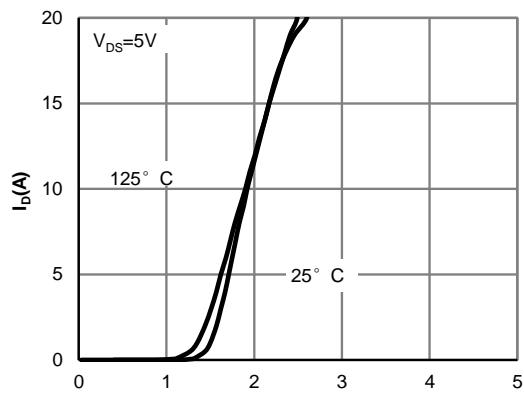
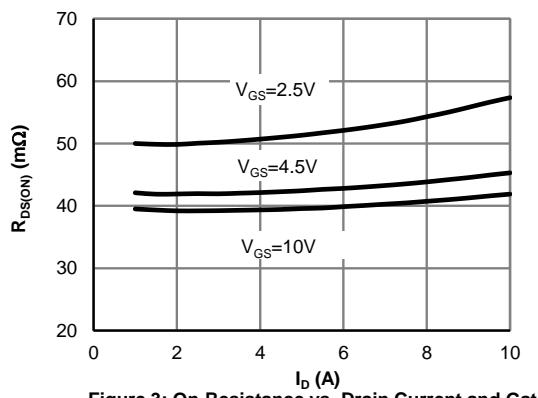
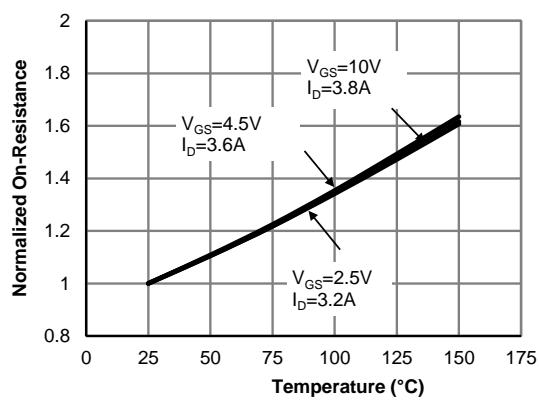
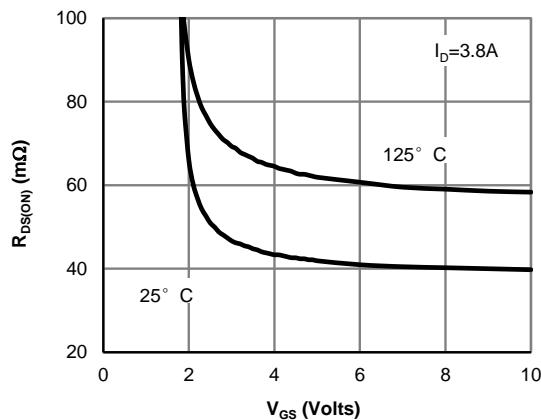
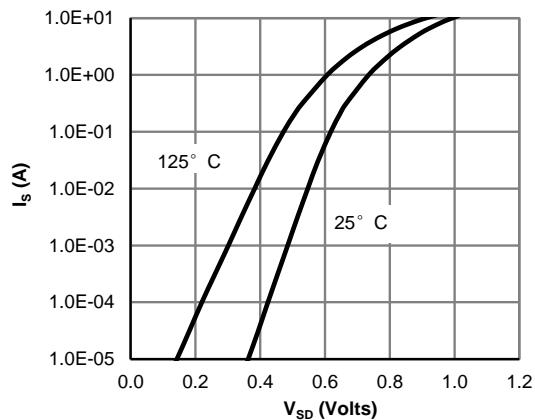
E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.

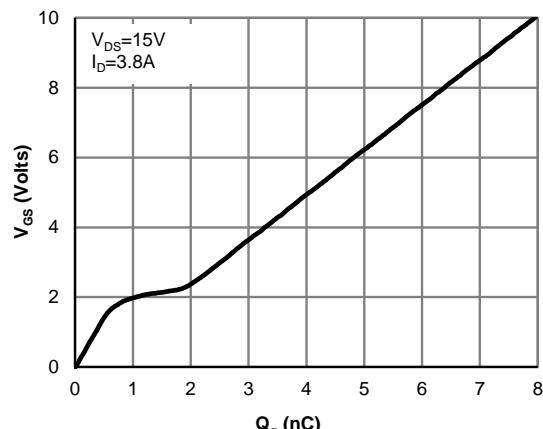
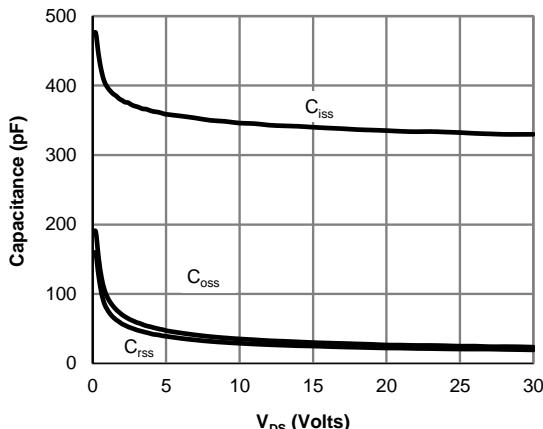
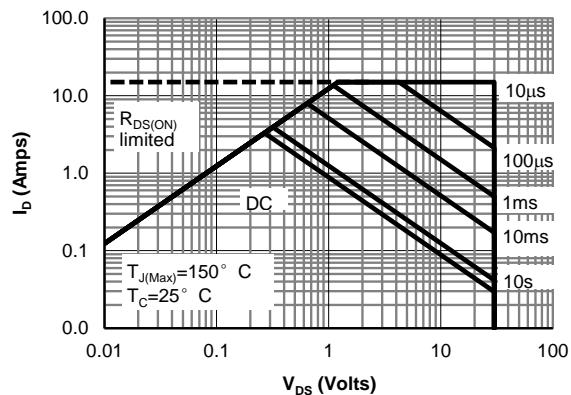
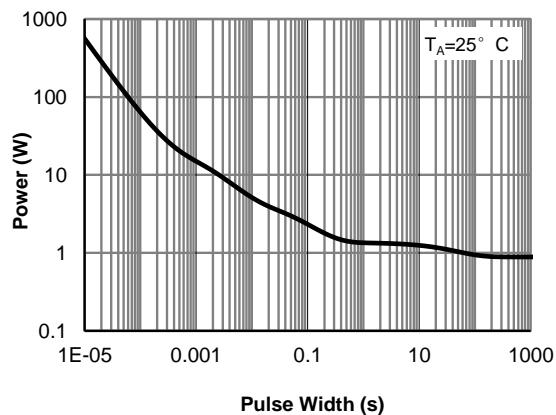
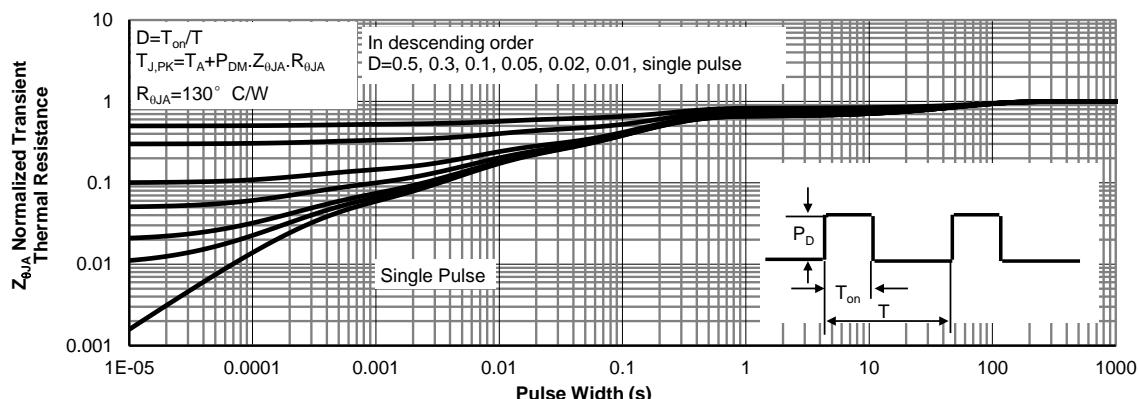
F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

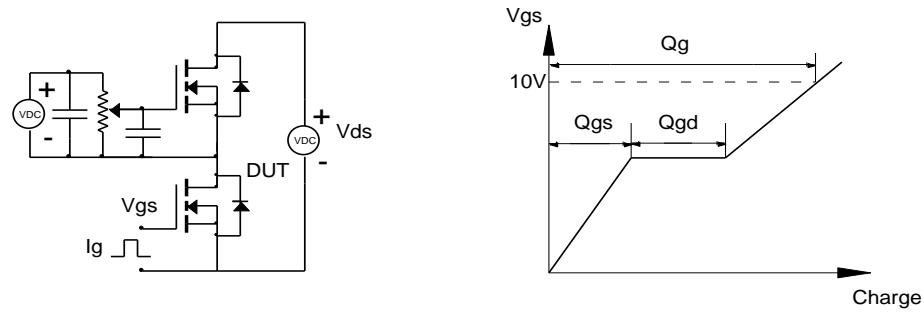
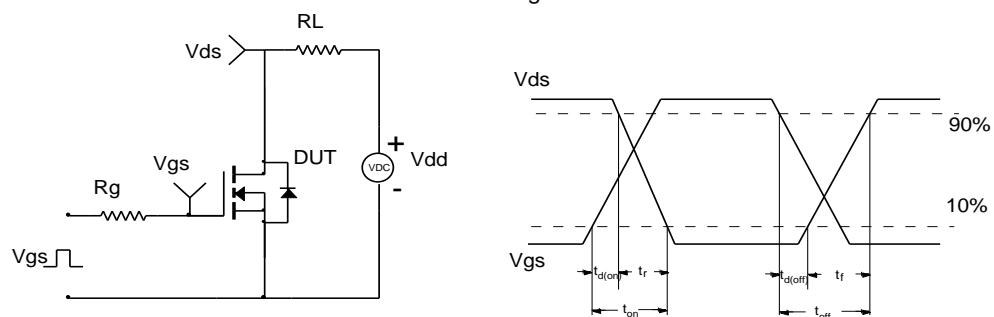
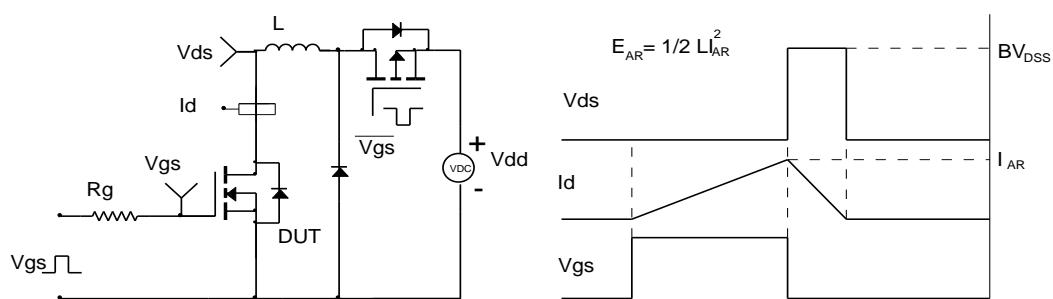
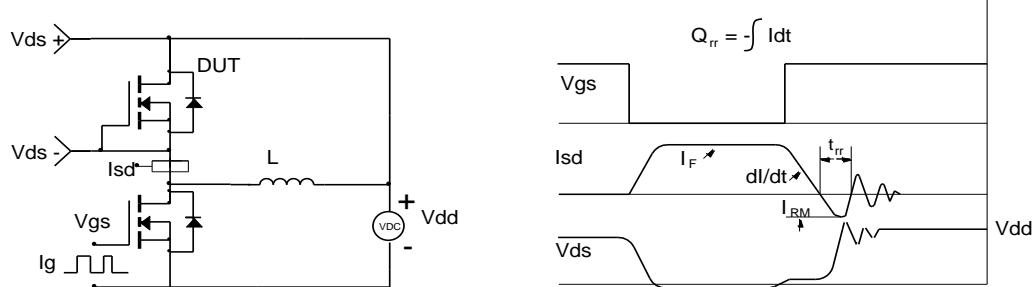
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N-Channel: TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 1: On-Region Characteristics (Note E)

Figure 2: Transfer Characteristics (Note E)

Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

Figure 4: On-Resistance vs. Junction Temperature (Note E)

Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

Figure 6: Body-Diode Characteristics (Note E)

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Figure 7: Gate-Charge Characteristics

Figure 8: Capacitance Characteristics

Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms


P-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$I_D=-250\mu\text{A}, V_{GS}=0\text{V}$	-20			V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=-20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$			-1 -5	μA
I_{GSS}	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$			± 10	μA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu\text{A}$	-0.15	-0.55	-0.95	V
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=-4.5\text{V}, I_D=-4.5\text{A}$ $T_J=125^\circ\text{C}$		36 46	44 56	$\text{m}\Omega$
		$V_{GS}=-2.5\text{V}, I_D=-4\text{A}$		46	59	$\text{m}\Omega$
		$V_{GS}=-1.8\text{V}, I_D=-3\text{A}$		60	80	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$V_{DS}=-5\text{V}, I_D=-4.5\text{A}$		26		S
V_{SD}	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		-0.7	-1	V
I_S	Maximum Body-Diode Continuous Current				-2	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-10\text{V}, f=1\text{MHz}$		930		pF
C_{oss}	Output Capacitance			90		pF
C_{rss}	Reverse Transfer Capacitance			80		pF
R_g	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		15	30	Ω
SWITCHING PARAMETERS						
$Q_g(4.5\text{V})$	Total Gate Charge	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, I_D=-4.5\text{A}$		8.5	17	nC
Q_{gs}	Gate Source Charge			1		nC
Q_{gd}	Gate Drain Charge			2.5		nC
$t_{D(\text{on})}$	Turn-On DelayTime	$V_{GS}=-4.5\text{V}, V_{DS}=-10\text{V}, R_L=2.22\Omega, R_{\text{GEN}}=3\Omega$		12		ns
t_r	Turn-On Rise Time			11		ns
$t_{D(\text{off})}$	Turn-Off DelayTime			82		ns
t_f	Turn-Off Fall Time			35		ns
t_{rr}	Body Diode Reverse Recovery Time	$I_F=-4.5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		25		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$I_F=-4.5\text{A}, dI/dt=500\text{A}/\mu\text{s}$		37		nC

A. The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_0 is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JUL} and lead to ambient.

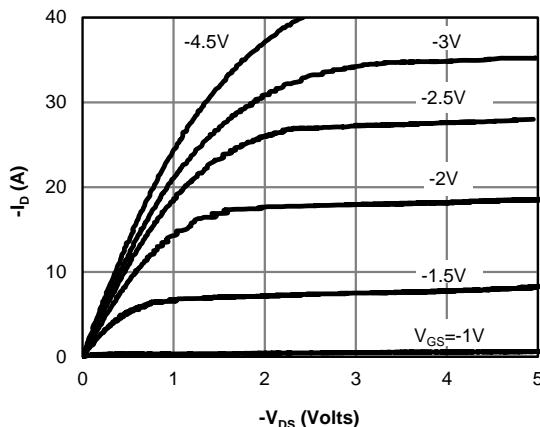
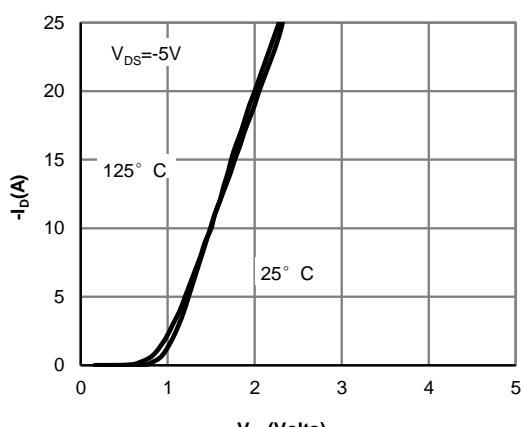
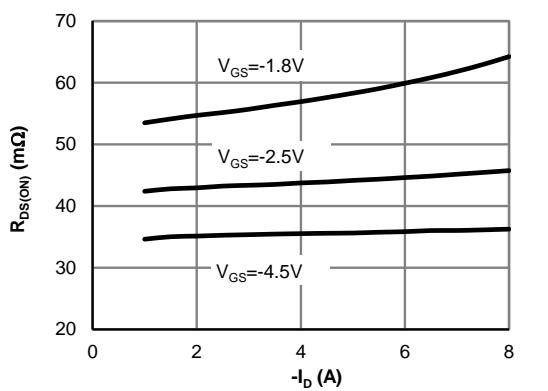
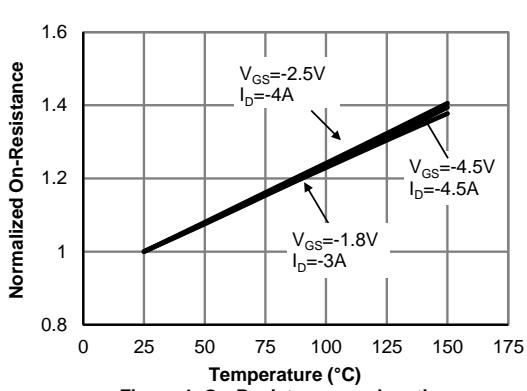
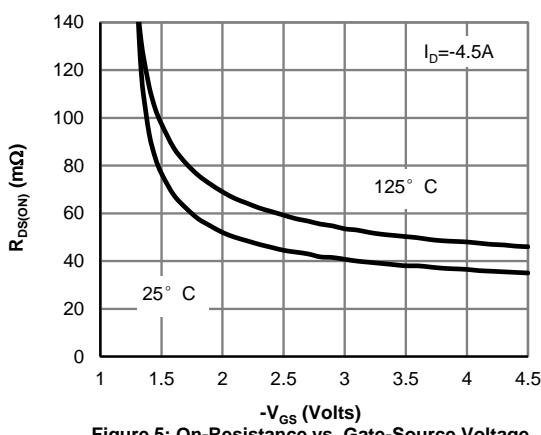
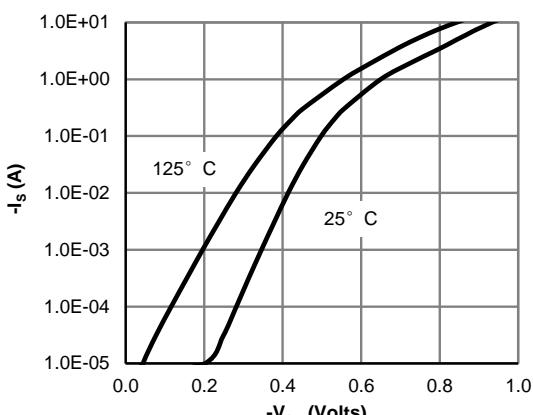
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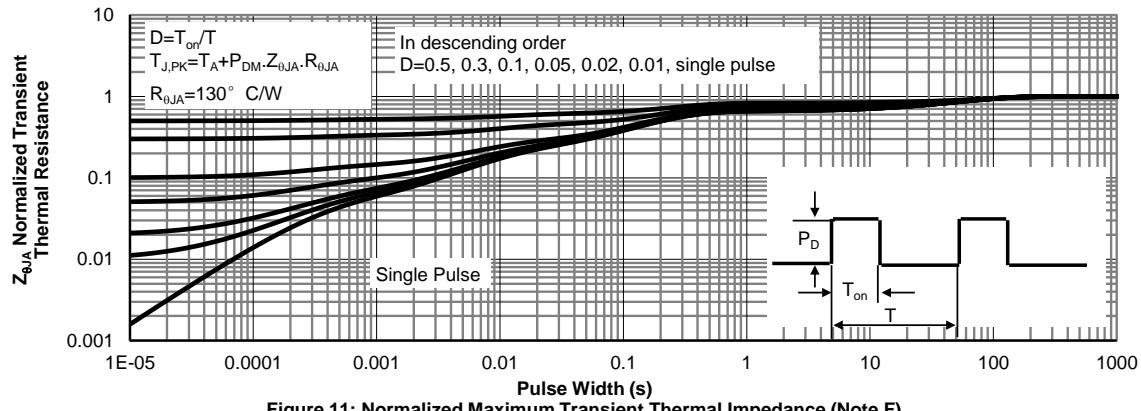
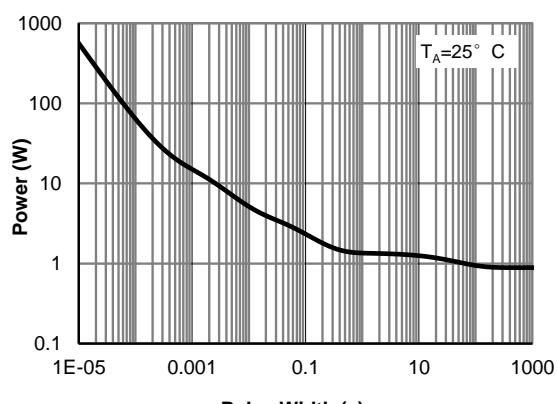
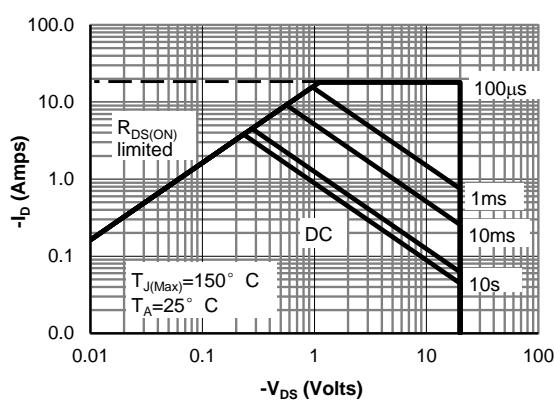
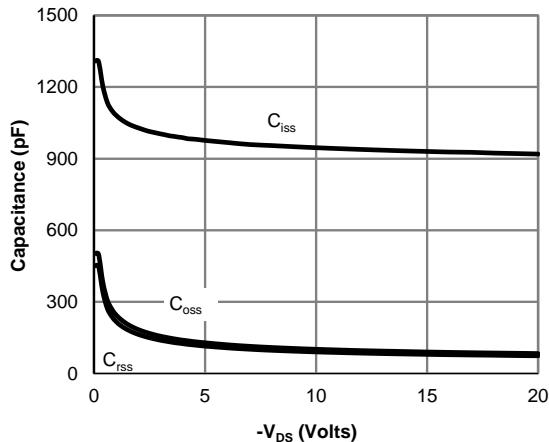
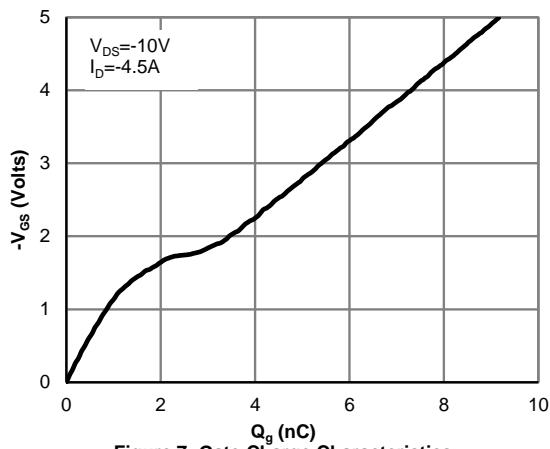
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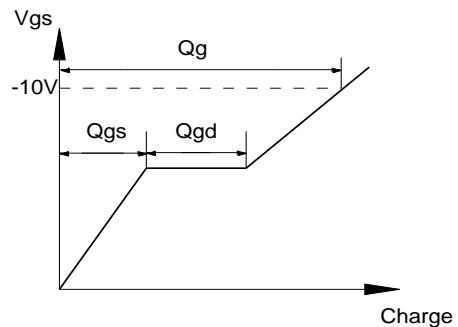
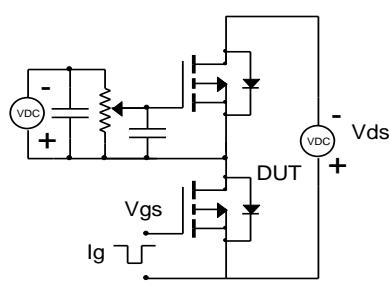
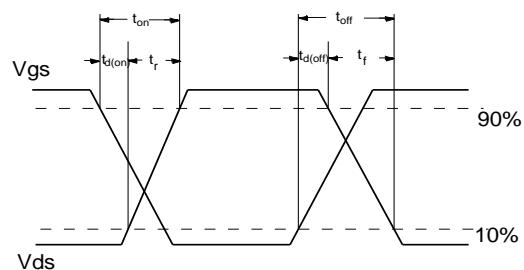
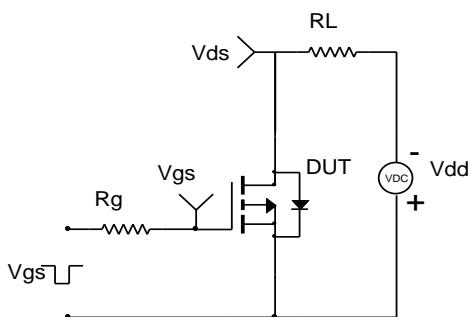
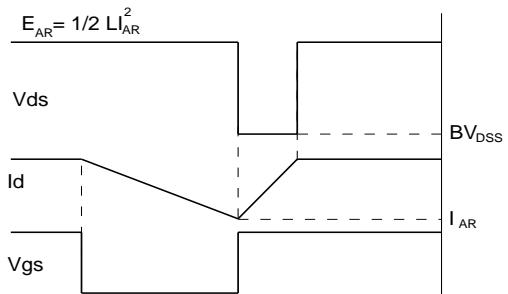
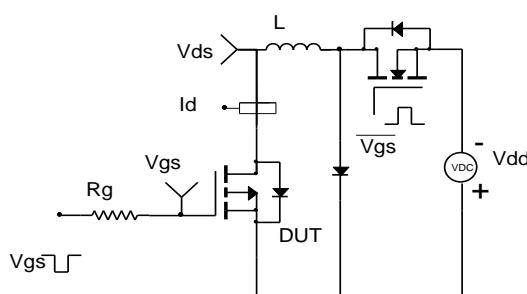
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